TOSHIBA FIELD EFFECT TRANSISTOR SILICON P CHANNEL MOS TYPE (HIGH SPEED U-MOSII)

TPC8104-H

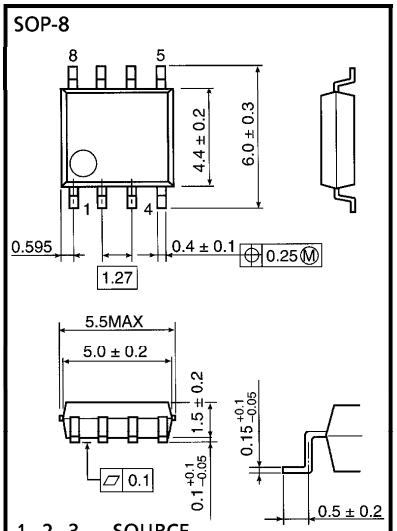
LITHIUM ION BATTERY APPLICATIONS

NOTE BOOK PC, PORTABLE EQUIPMENTS APPLICATIONS

HIGH SPEED AND HIGH EFFICIENCY DC-DC CONVERTERS

INDUSTRIAL APPLICATIONS

Unit in mm



JEDEC	—
EIAJ	—
TOSHIBA	2-6J1A

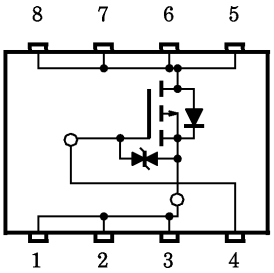
Weight : 0.08 g

- High Speed Switching
- Small Gate Charge : Q_g = 17 nC (Typ.)
- Low Drain-Source ON Resistance : $R_{DS\,(ON)}$ = 38 mΩ (Typ.)
- High Forward Transfer Admittance : $|Y_{fs}|$ = 7.0 S (Typ.)
- Low Leakage Current : I_{DSS} = −10 μA (Max.) (V_{DS} = − 30 V)
- Enhancement-Mode : V_{th} = −0.8~−2.0 V (V_{DS} = −10 V, I_D = −1 mA)

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT
Drain-Source Voltage		V_{DSS}	−30	V
Drain-Gate Voltage (R_{GS} = 20 kΩ)		V_{DGR}	−30	V
Gate-Source Voltage		V_{GSS}	±20	V
Drain Current	DC	I_D	−5	A
	Pulse	I_{DP}	−20	A
Drain Power Dissipation (Ta = 25°C)***		P_D	2.4	W
Single Pulse Avalanche Energy**		E_{AS}	32.5	mJ
Avalanche Current		I_{AR}	−5	A
Repetitive Avalanche Energy*		E_{AR}	0.24	mJ
Channel Temperature		T_{ch}	150	°C
Storage Temperature Range		T_{stg}	−55~150	°C

CIRCUIT CONFIGURATION



THERMAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance, Channel to Ambient***	$R_{th\,(ch\text{-}a)}$	52.1	°C / W

Note ;

* Repetitive rating ; Pulse Width Limited by Max. Junction temperature.

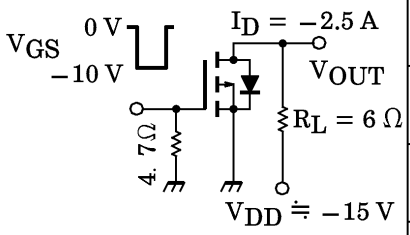
** V_{DD} = −24 V, T_{ch} = 25°C (initial), L = 1.0 mH, R_G = 25 Ω, I_{AR} = −5 A

*** Drive operation ; Mount on glass epoxy board [1 $inch^2$ × 0.8 t] (t = 10 s)

This transistor is an electrostatic sensitive device. Please handle with caution.

961001EAA1

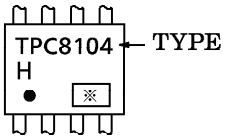
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current		I_{GSS}	$V_{GS} = \pm 16$ V, $V_{DS} = 0$ V	—	—	±10	μA
Drain Cut-Off Current		I_{DSS}	$V_{DS} = -30$ V, $V_{GS} = 0$ V	—	—	−10	μA
Drain-Source Breakdown Voltage		$V_{(BR)\ DSS}$	$I_D = -10$ mA, $V_{GS} = 0$ V	−30	—	—	V
		$V_{(BR)\ DSX}$	$I_D = -10$ mA, $V_{GS} = 20$ V	−15	—	—	
Gate Threshold Voltage		V_{th}	$V_{DS} = -10$ V, $I_D = -1$ mA	−0.8	—	−2.0	V
Drain-Source ON Resistance		$R_{DS\ (ON)}$	$V_{GS} = -4$ V, $I_D = -2.5$ A	—	68	120	mΩ
		$R_{DS\ (ON)}$	$V_{GS} = -10$ V, $I_D = -2.5$ A	—	38	65	
Forward Transfer Admittance		$\|Y_{fs}\|$	$V_{DS} = -10$ V, $I_D = -2.5$ A	3.5	7.0	—	S
Input Capacitance		C_{iss}	$V_{DS} = -10$ V, $V_{GS} = 0$ V, f = 1 MHz	—	730	—	pF
Reverse Transfer Capacitance		C_{rss}		—	190	—	
Output Capacitance		C_{oss}		—	270	—	
Switching Time	Rise Time	t_r		—	8	—	ns
	Turn-On Time	t_{on}		—	15	—	
	Fall Time	t_f		—	26	—	
	Turn-Off Time	t_{off}	V_{IN} : t_r, $t_f < 5$ ns, Duty ≦ 1%, $t_w = 10$ μs	—	76	—	
Total Gate Charge (Gate-Source Plus Gate-Drain)		Q_g	$V_{DD} \fallingdotseq -24$ V, $V_{GS} = -10$ V, $I_D = -5$ A	—	17	—	nC
Gate-Source Charge		Q_{gs}		—	13	—	
Gate-Drain (“Miller”) Charge		Q_{gd}		—	4	—	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Continuous Drain Reverse Current	I_{DR}	—	—	—	−5	A
Pulse Drain Reverse Current	I_{DRP}	—	—	—	−20	A
Diode Forward Voltage	V_{DSF}	$I_{DR} = -5$ A, $V_{GS} = 0$ V	—	—	1.2	V

MARKING

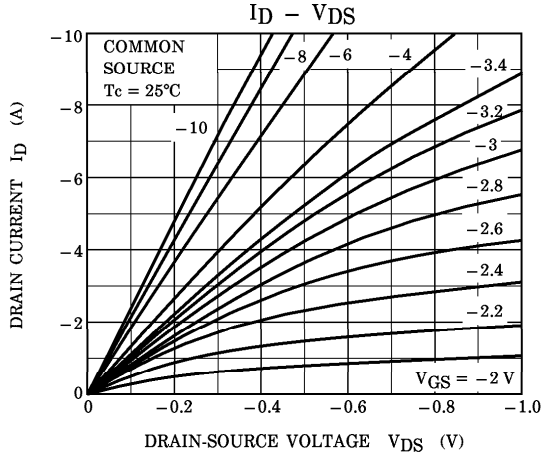


※ Lot Number

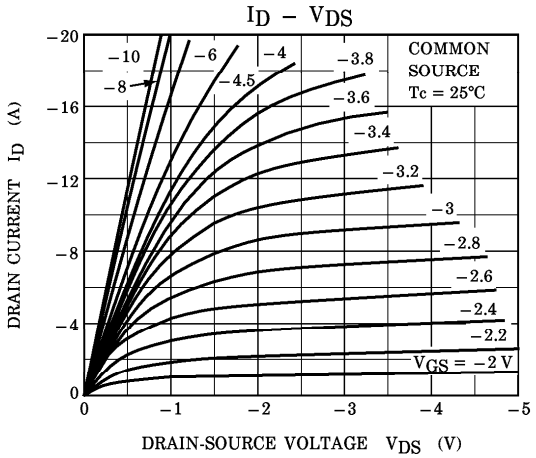
□□ — Month (Starting from Alphabet A)

Year (Last Number of the Christian Era)

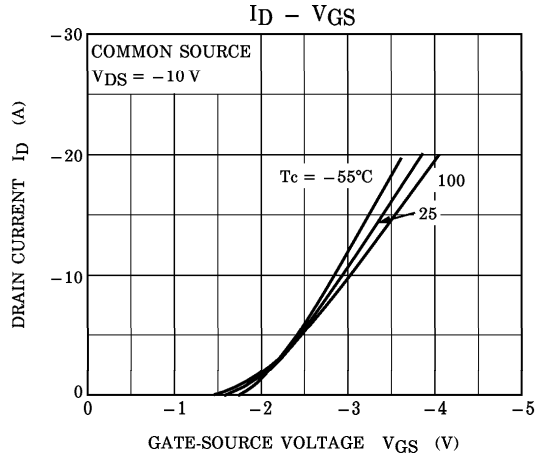
$I_D - V_{DS}$



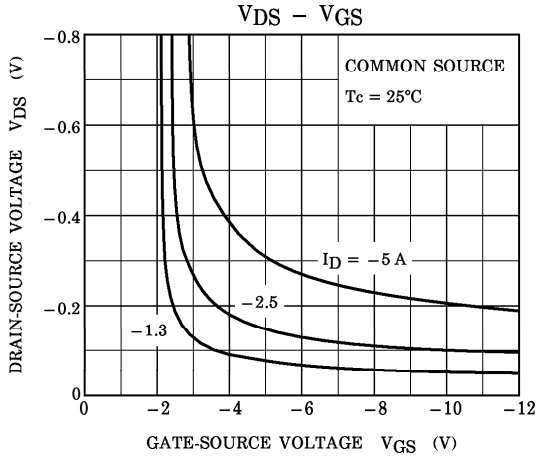
$I_D - V_{DS}$



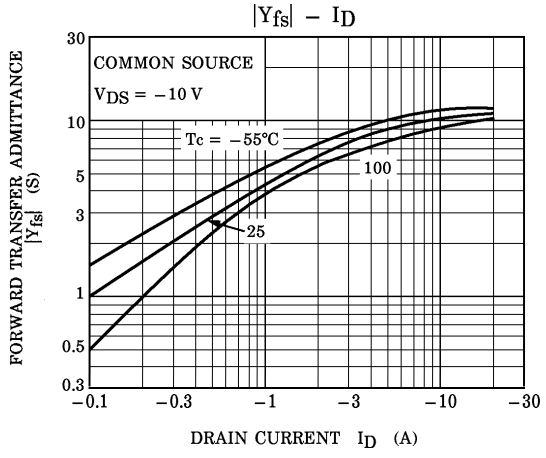
$I_D - V_{GS}$



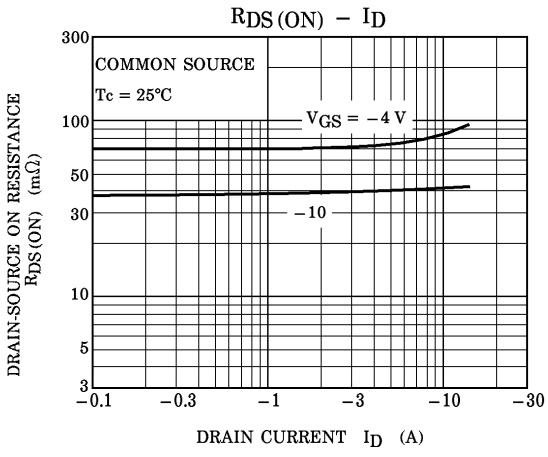
$V_{DS} - V_{GS}$



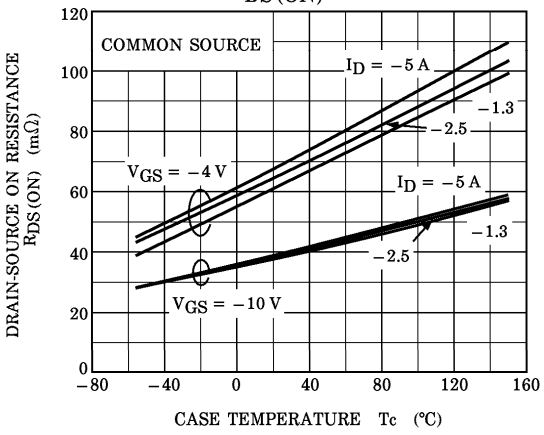
$|Y_{fs}| - I_D$



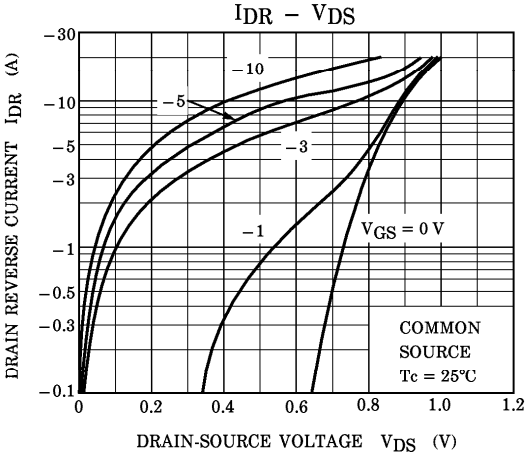
$R_{DS(ON)} - I_D$



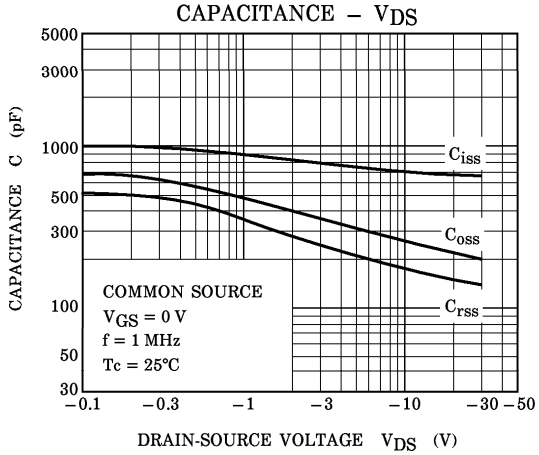
$R_{DS\,(ON)}$ – Tc



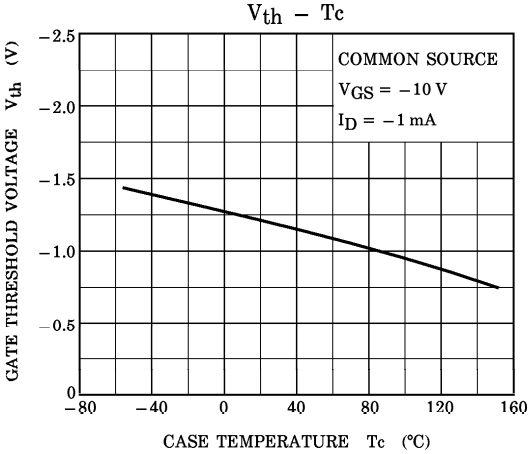
I_{DR} – V_{DS}



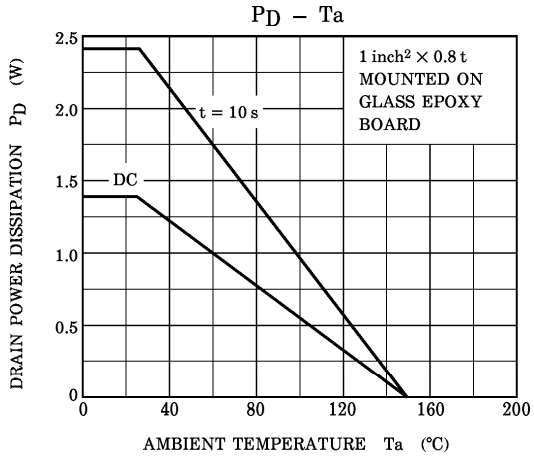
CAPACITANCE – V_{DS}



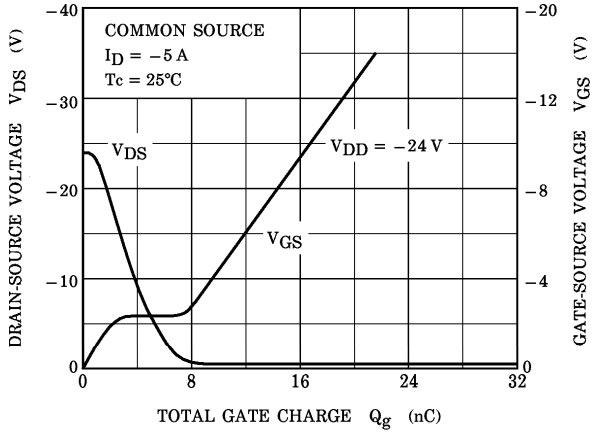
V_{th} – Tc



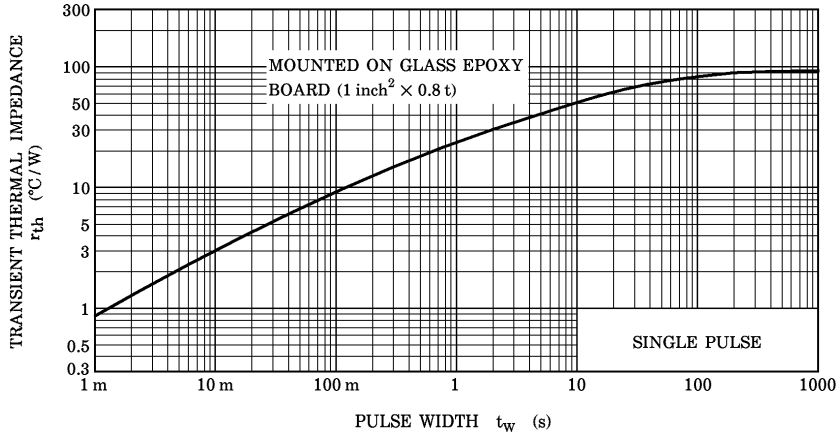
P_D – Ta



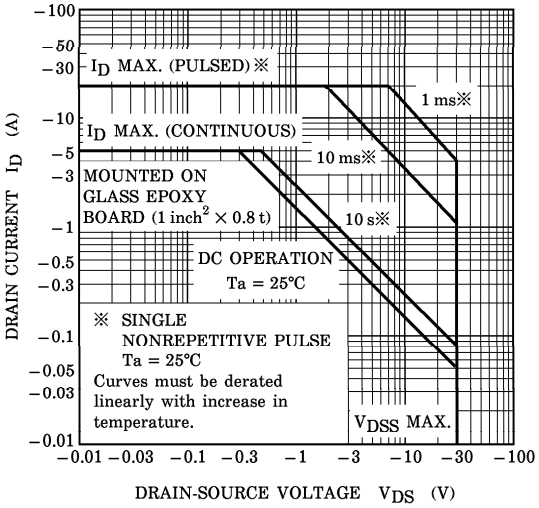
DYNAMIC INPUT / OUTPUT CHARACTERISTICS



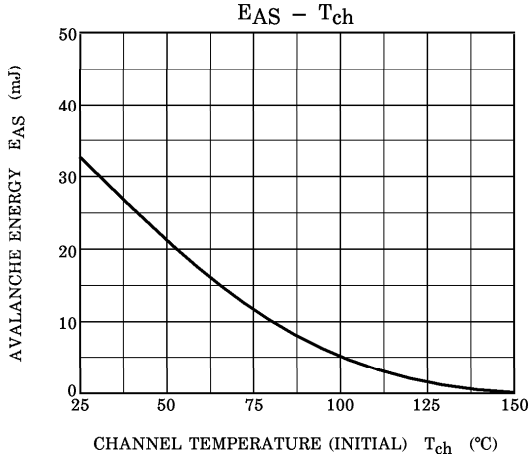
r_{th} – t_w

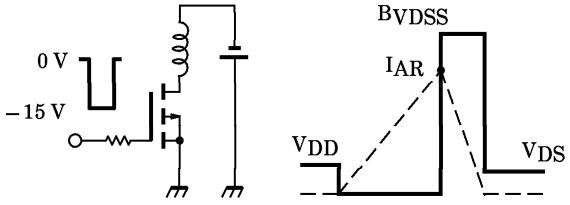


SAFE OPERATING AREA



E_{AS} – T_{ch}





TEST CIRCUIT WAVE FORM

Peak I_{AR} = −5 A, R_G = 25 Ω
V_{DD} = −24 V, L = 1.0 mH

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$